



Chipsmall Limited consists of a professional team with an average of over 10 year of expertise in the distribution of electronic components. Based in Hongkong, we have already established firm and mutual-benefit business relationships with customers from,Europe,America and south Asia,supplying obsolete and hard-to-find components to meet their specific needs.

With the principle of “Quality Parts,Customers Priority,Honest Operation,and Considerate Service”,our business mainly focus on the distribution of electronic components. Line cards we deal with include Microchip,ALPS,ROHM,Xilinx,Pulse,ON,Everlight and Freescale. Main products comprise IC,Modules,Potentiometer,IC Socket,Relay,Connector.Our parts cover such applications as commercial,industrial, and automotives areas.

We are looking forward to setting up business relationship with you and hope to provide you with the best service and solution. Let us make a better world for our industry!



## Contact us

Tel: +86-755-8981 8866 Fax: +86-755-8427 6832

Email & Skype: info@chipsmall.com Web: www.chipsmall.com

Address: A1208, Overseas Decoration Building, #122 Zhenhua RD., Futian, Shenzhen, China

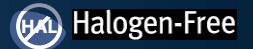


# EPC2106 – Enhancement-Mode GaN Power Transistor Half-Bridge

$V_{DS}$ , 100 V

$R_{DS(on)}$ , 70 mΩ

$I_D$ , 1.7 A

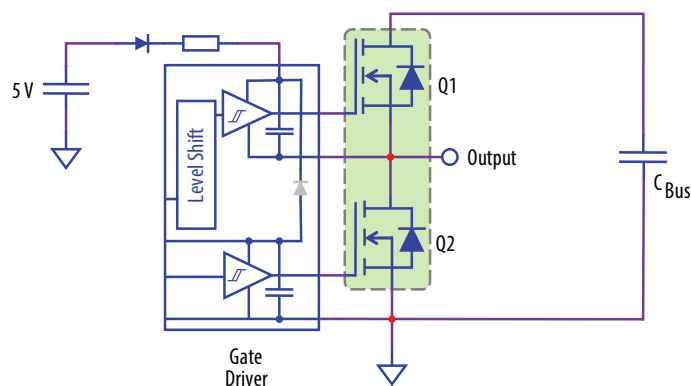


Gallium Nitride is grown on Silicon Wafers and processed using standard CMOS equipment leveraging the infrastructure that has been developed over the last 60 years. GaN's exceptionally high electron mobility and low temperature coefficient allows very low  $R_{DS(on)}$ , while its lateral device structure and majority carrier diode provide exceptionally low  $Q_G$  and zero  $Q_{RR}$ . The end result is a device that can handle tasks where very high switching frequency, and low on-time are beneficial as well as those where on-state losses dominate.

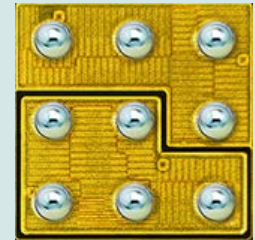
Maximum Ratings			
DEVICE	PARAMETER		UNIT
Q1 & Q2	$V_{DS}$	Drain-to-Source Voltage (Continuous)	100
		Drain-to-Source Voltage (up to 10,000 5 ms pulses at 150°C)	120
	$I_D$	Continuous ( $T_A = 25^\circ\text{C}$ , $R_{\theta JA} = 320^\circ\text{C/W}$ )	1.7
		Pulsed ( $25^\circ\text{C}$ , $T_{PULSE} = 300 \mu\text{s}$ )	18
	$V_{GS}$	Gate-to-Source Voltage	6
		Gate-to-Source Voltage	-4
$T_J$	Operating Temperature	-40 to 150	
$T_{STG}$	Storage Temperature	-40 to 150	

Thermal Characteristics			
PARAMETER		TYP	UNIT
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	3	°C/W
$R_{\theta JB}$	Thermal Resistance, Junction-to-Board	30	
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient (Note 1)	81	

Note 1:  $R_{\theta JA}$  is determined with the device mounted on one square inch of copper pad, single layer 2 oz copper on FR4 board. See [http://epc-co.com/epc/documents/product-training/Appnote\\_Thermal\\_Performance\\_of\\_eGaN\\_FETs.pdf](http://epc-co.com/epc/documents/product-training/Appnote_Thermal_Performance_of_eGaN_FETs.pdf) for details



Typical Application Circuit



EPC2106 eGaN® ICs are supplied only in passivated die form with solder bumps  
Die Size: 1.35 mm x 1.35 mm

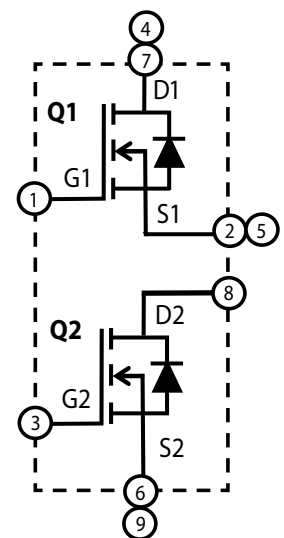
**Applications**

- High Frequency DC-DC Conversion
- Class-D Audio

**Benefits**

- Ultra High Efficiency
- Ultra Low  $R_{DS(on)}$
- Ultra Low  $Q_G$
- Ultra Small Footprint

[www.epc-co.com/epc/Products/eGaNfetsandICs/EPC2106.aspx](http://www.epc-co.com/epc/Products/eGaNfetsandICs/EPC2106.aspx)



EPC2106 – Detailed Schematic

Static Characteristics ( $T_J = 25^\circ\text{C}$  unless otherwise stated)

DEVICE	PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
Q1 & Q2	$BV_{DSS}$	Drain-to-Source Voltage	$V_{GS} = 0\text{ V}, I_D = 0.3\text{ mA}$	100			V
	$I_{DSS}$	Drain-Source Leakage	$V_{DS} = 80\text{ V}, V_{GS} = 0\text{ V}$		0.001	0.25	mA
	$I_{GSS}$	Gate-to-Source Forward Leakage	$V_{GS} = 5\text{ V}$		0.01	1	mA
		Gate-to-Source Reverse Leakage	$V_{GS} = -4\text{ V}$		0.001	0.25	mA
	$V_{GS(TH)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 0.6\text{ mA}$	0.8	1.4	2.5	V
	$R_{DS(on)}$	Drain-Source On Resistance	$V_{GS} = 5\text{ V}, I_D = 2\text{ A}$		55	70	m $\Omega$
	$V_{SD}$	Source-Drain Forward Voltage	$I_S = 0.35\text{ A}, V_{GS} = 0\text{ V}$		2.1		V

Dynamic Characteristics ( $T_J = 25^\circ\text{C}$  unless otherwise stated)

DEVICE	PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
Q1	$C_{ISS}$	Input Capacitance	$V_{DS} = 50\text{ V}, V_{GS} = 0\text{ V}$		79	95	pF
	$C_{RSS}$	Reverse Transfer Capacitance			0.5		
	$C_{OSS}$	Output Capacitance			52	78	
	$C_{OSS(ER)}$	Effective Output Capacitance, Energy Related (Note 2)	$V_{DS} = 0\text{ to }50\text{ V}, V_{GS} = 0\text{ V}$		63		pF
	$C_{OSS(TR)}$	Effective Output Capacitance, Time Related (Note 3)			79		
	$R_G$	Gate Resistance			0.6		$\Omega$
	$Q_G$	Total Gate Charge	$V_{DS} = 50\text{ V}, V_{GS} = 5\text{ V}, I_D = 2\text{ A}$		730	900	pC
	$Q_{GS}$	Gate to Source Charge	$V_{DS} = 50\text{ V}, I_D = 2\text{ A}$		240		
	$Q_{GD}$	Gate to Drain Charge			140		
	$Q_{G(TH)}$	Gate Charge at Threshold			165		
	$Q_{OSS}$	Output Charge	$V_{DS} = 50\text{ V}, V_{GS} = 0\text{ V}$		3960	5940	
	$Q_{RR}$	Source-Drain Recovery Charge			0		
Q2	$C_{ISS}$	Input Capacitance	$V_{DS} = 50\text{ V}, V_{GS} = 0\text{ V}$		79	95	pF
	$C_{RSS}$	Reverse Transfer Capacitance			0.5		
	$C_{OSS}$	Output Capacitance			61	92	
	$C_{OSS(ER)}$	Effective Output Capacitance, Energy Related (Note 2)	$V_{DS} = 0\text{ to }50\text{ V}, V_{GS} = 0\text{ V}$		74		pF
	$C_{OSS(TR)}$	Effective Output Capacitance, Time Related (Note 3)			94		
	$R_G$	Gate Resistance			0.6		$\Omega$
	$Q_G$	Total Gate Charge	$V_{DS} = 50\text{ V}, V_{GS} = 5\text{ V}, I_D = 2\text{ A}$		730	900	pC
	$Q_{GS}$	Gate to Source Charge	$V_{DS} = 50\text{ V}, I_D = 2\text{ A}$		240		
	$Q_{GD}$	Gate to Drain Charge			140		
	$Q_{G(TH)}$	Gate Charge at Threshold			165		
	$Q_{OSS}$	Output Charge	$V_{DS} = 50\text{ V}, V_{GS} = 0\text{ V}$		4680	7020	
	$Q_{RR}$	Source-Drain Recovery Charge			0		

Note 2:  $C_{OSS(ER)}$  is a fixed capacitance that gives the same stored energy as  $C_{OSS}$  while  $V_{DS}$  is rising from 0 to 50%  $BV_{DSS}$ .

Note 3:  $C_{OSS(TR)}$  is a fixed capacitance that gives the same charging time as  $C_{OSS}$  while  $V_{DS}$  is rising from 0 to 50%  $BV_{DSS}$ .

Figure 1 (Q1 & Q2): Typical Output Characteristics at 25°C

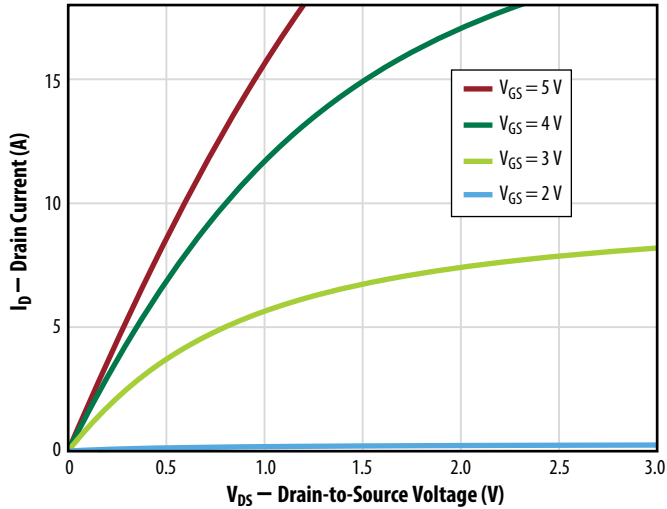


Figure 2 (Q1 & Q2): Transfer Characteristics

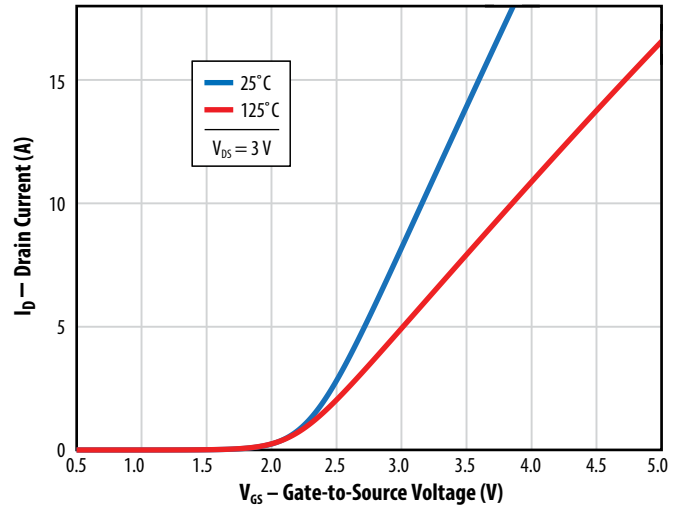


Figure 3 (Q1 & Q2):  $R_{DS(on)}$  vs.  $V_{GS}$  for Various Drain Currents

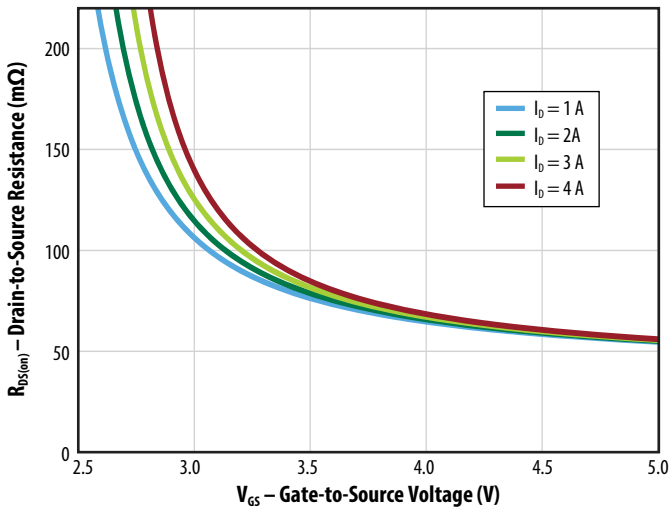


Figure 4 (Q1 & Q2):  $R_{DS(on)}$  vs.  $V_{GS}$  for Various Temperatures

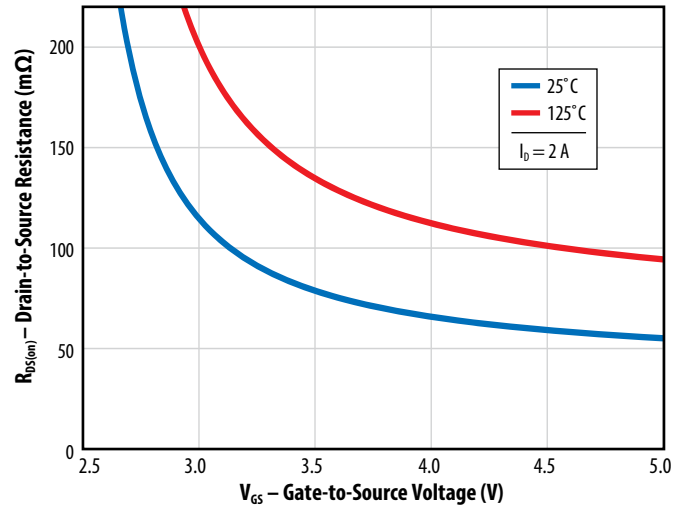


Figure 5a (Q1): Capacitance (Linear Scale)

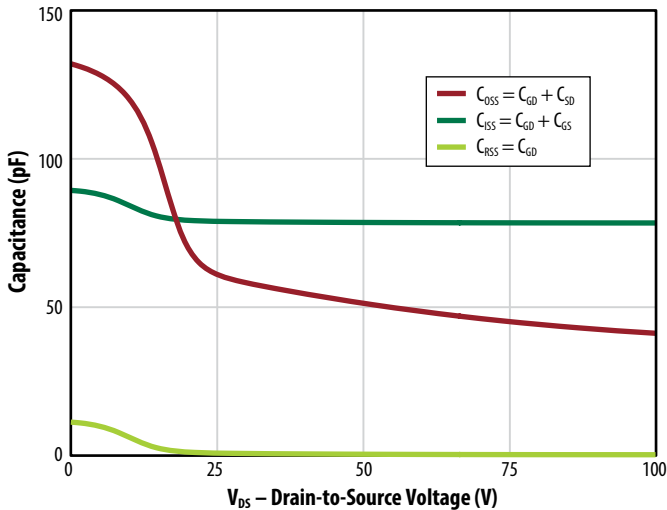


Figure 5b (Q1): Capacitance (Log Scale)

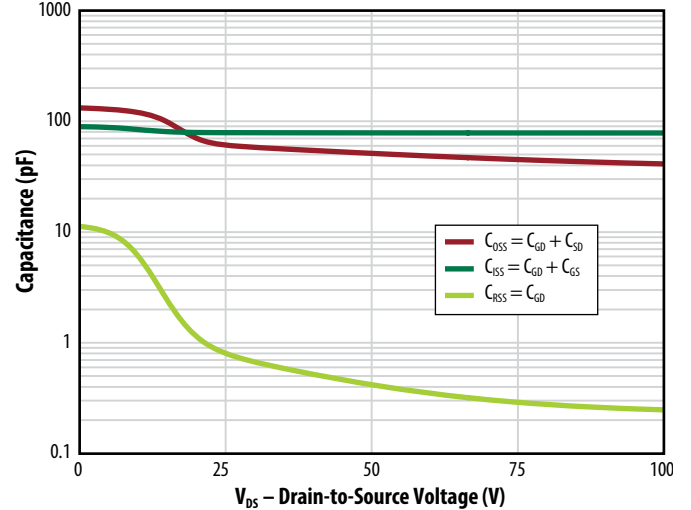


Figure 5c (Q2): Capacitance (Linear Scale)

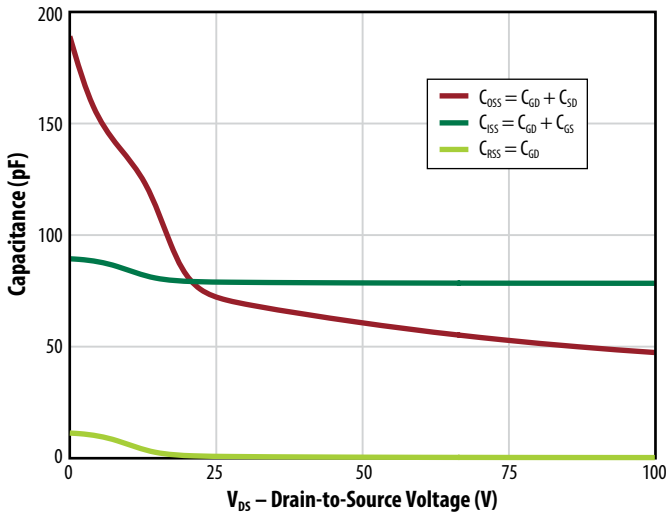


Figure 5d (Q2): Capacitance (Log Scale)

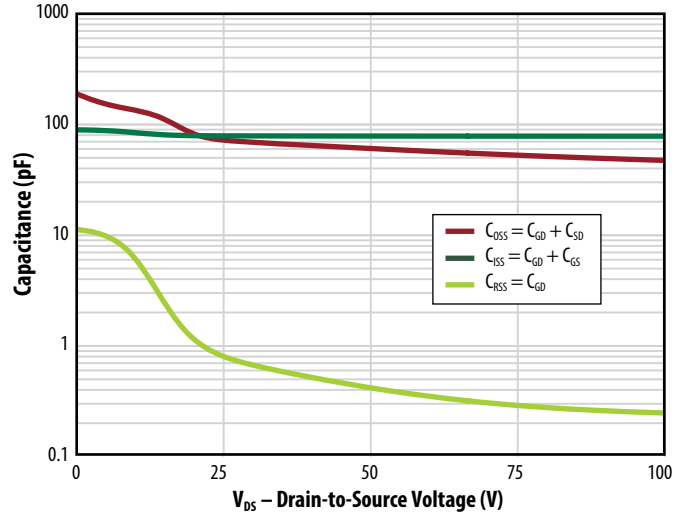


Figure 6a (Q1): Output Charge and C\_oss Stored Energy

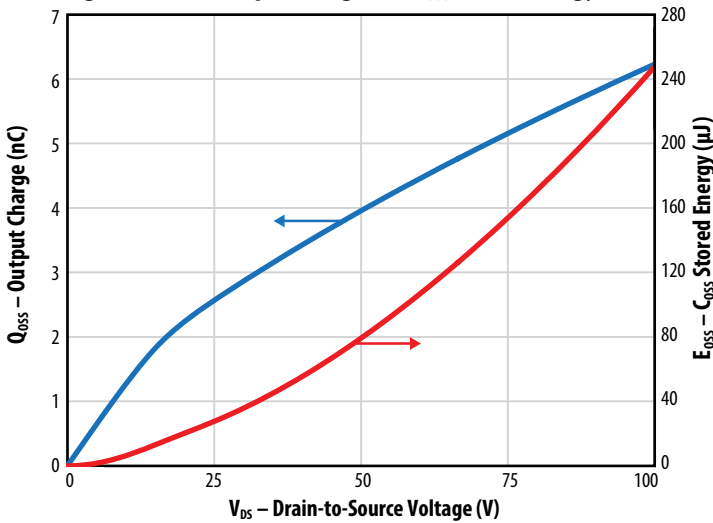


Figure 6b (Q2): Output Charge and C\_oss Stored Energy

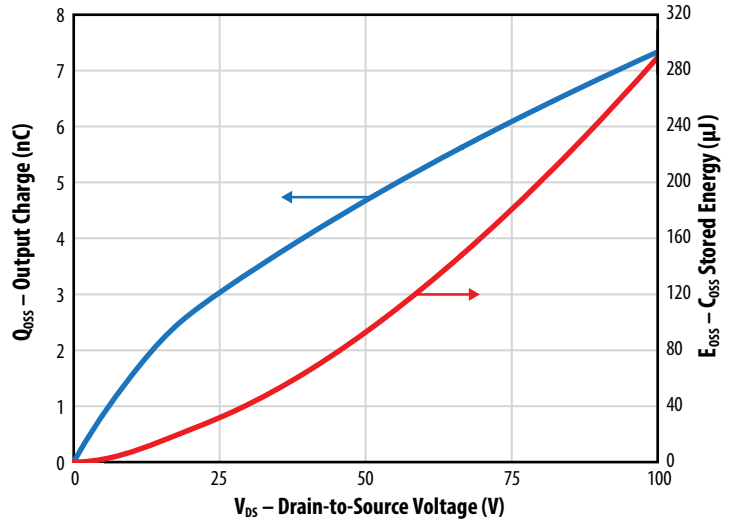


Figure 7 (Q1 & Q2): Gate Charge

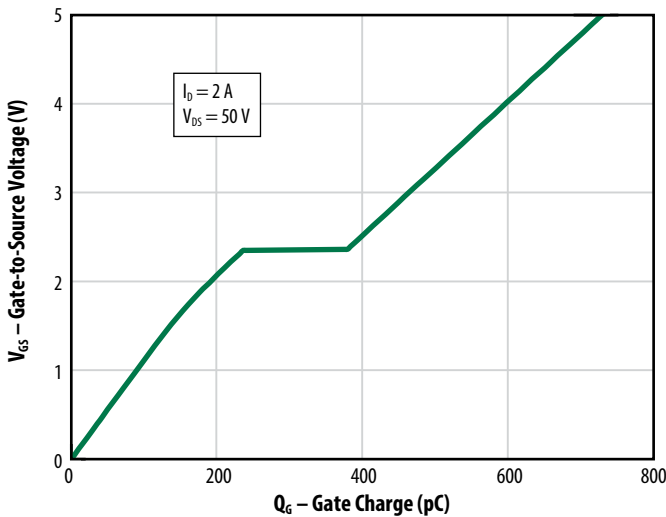
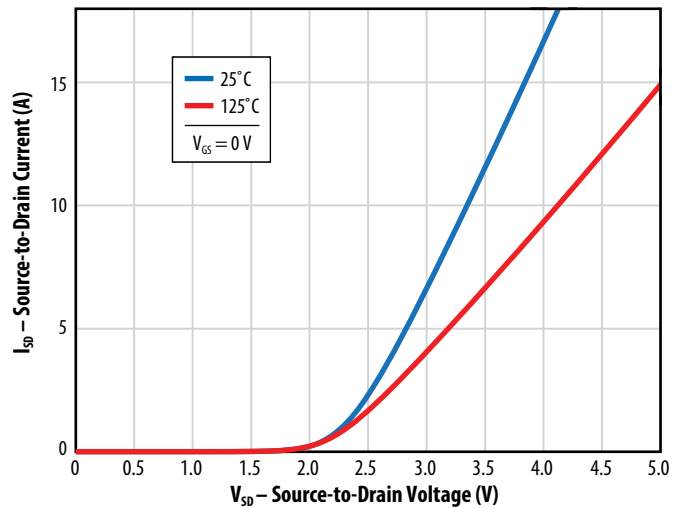
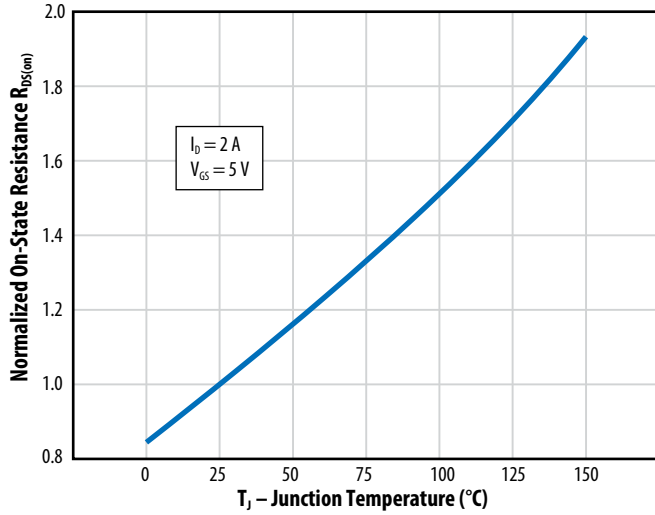


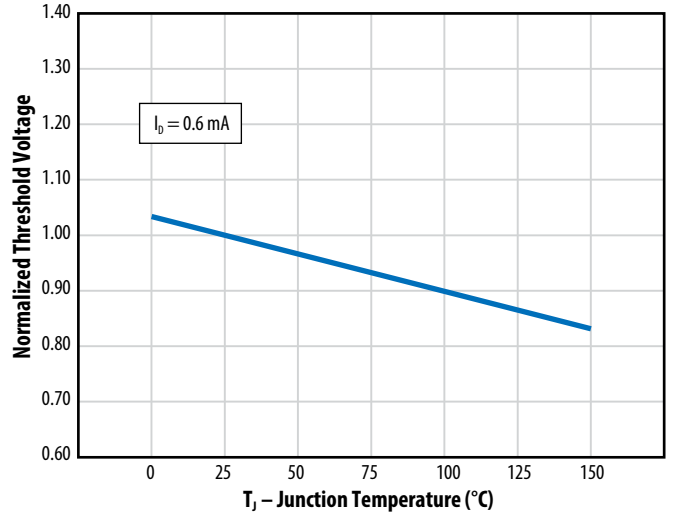
Figure 8 (Q1 & Q2): Reverse Drain-Source Characteristics



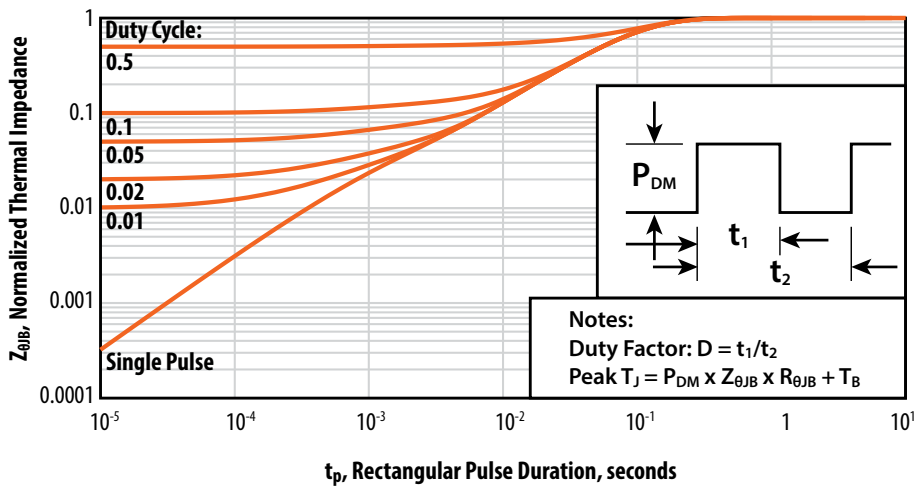
**Figure 9 (Q1 & Q2):  
Normalized On-State Resistance vs. Temperature**



**Figure 10 (Q1 & Q2):  
Normalized Threshold Voltage vs. Temperature**



**(Q1 & Q2) Junction-to-Board**



**(Q1 & Q2) Junction-to-Case**

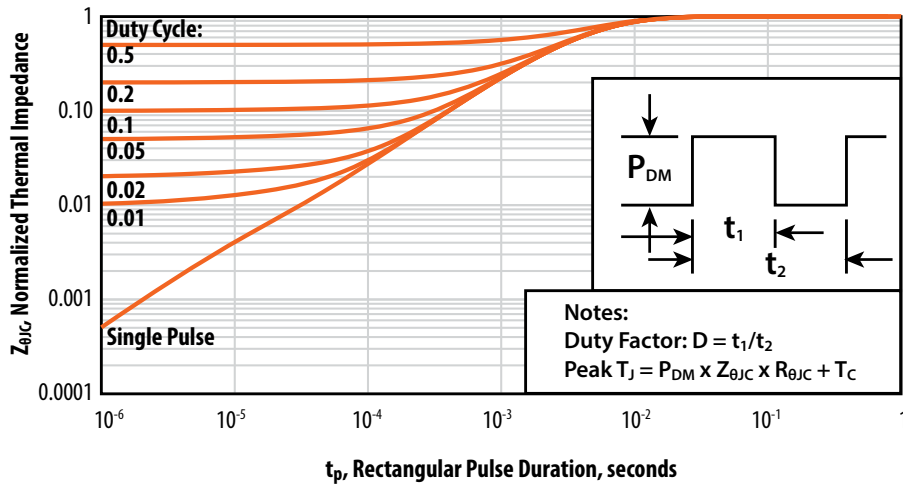
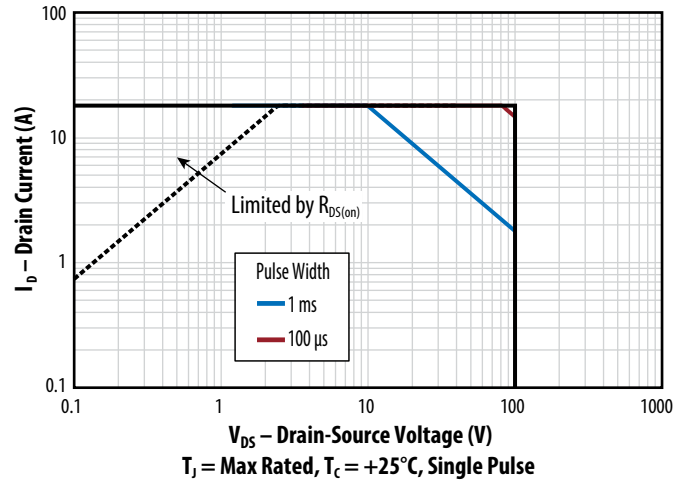
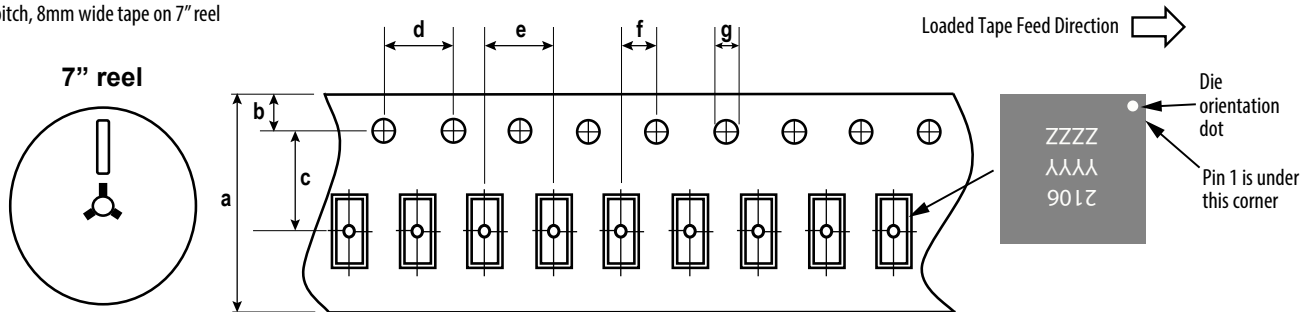


Figure 12 (Q1 & Q2): Safe Operating Area



**TAPE AND REEL CONFIGURATION**

4mm pitch, 8mm wide tape on 7" reel

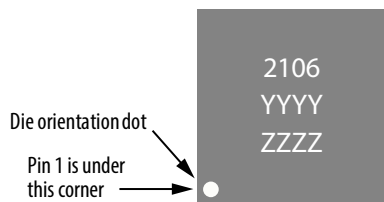


Die is placed into pocket solder bump side down (face side down)

Dimension (mm)	EPC2106 (note 1)		
	target	min	max
a	8.00	7.90	8.30
b	1.75	1.65	1.85
c (see note)	3.50	3.45	3.55
d	4.00	3.90	4.10
e	4.00	3.90	4.10
f (see note)	2.00	1.95	2.05
g	1.5	1.5	1.6

Note 1: MSL 1 (moisture sensitivity level 1) classified according to IPC/JEDEC industry standard.  
 Note 2: Pocket position is relative to the sprocket hole measured as true position of the pocket, not the pocket hole.

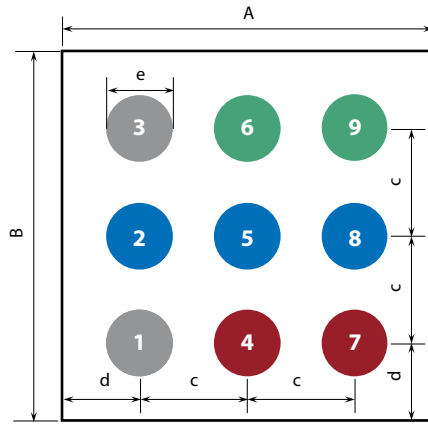
**DIE MARKINGS**



Part Number	Laser Markings		
	Part # Marking Line 1	Lot_Date Code Marking Line 2	Lot_Date Code Marking Line 3
EPC2106	2106	YYYY	ZZZZ

**DIE OUTLINE**

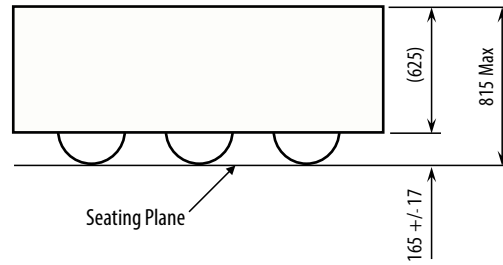
Solder Bump View



Pad 1 is Gate1 (high side)  
 Pad 3 is Gate2 (low side)  
 Pads 4, 7 are  $V_m$   
 Pads 2, 5, 8 are Switch Node  
 Pads 6, 9 are Ground

DIM	Micrometers		
	MIN	Nominal	MAX
A	1320	1350	1380
B	1320	1350	1380
c	450	450	450
d	210	225	240
e	187	208	229

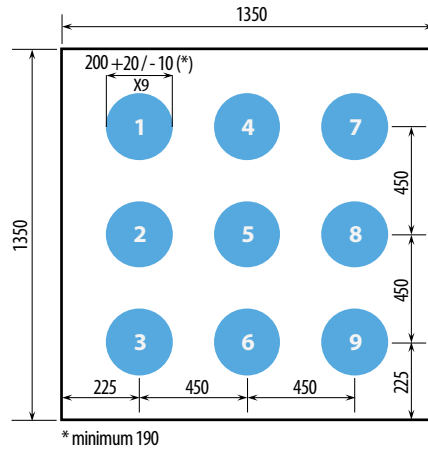
Side View



**RECOMMENDED**

**LAND PATTERN**

(measurements in  $\mu\text{m}$ )

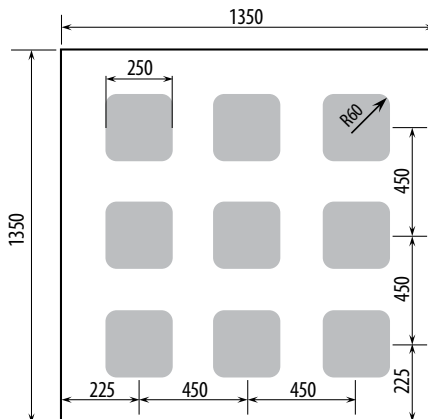


The land pattern is solder mask defined  
 Solder mask is 10  $\mu\text{m}$  smaller per side than bump

**RECOMMENDED**

**STENCIL DRAWING**

(measurements in  $\mu\text{m}$ )



Recommended stencil should be 4 mil (100  $\mu\text{m}$ ) thick, must be laser cut, openings per drawing.

Intended for use with SAC305 Type 4 solder, reference 88.5% metals content.

Additional assembly resources available at  
<http://epc-co.com/epc/DesignSupport/AssemblyBasics.aspx>

Efficient Power Conversion Corporation (EPC) reserves the right to make changes without further notice to any products herein to improve reliability, function or design. EPC does not assume any liability arising out of the application or use of any product or circuit described herein; neither does it convey any license under its patent rights, nor the rights of others.

eGaN® is a registered trademark of Efficient Power Conversion Corporation.  
 EPC Patent Listing: [epc-co.com/epc/AboutEPC/Patents.aspx](http://epc-co.com/epc/AboutEPC/Patents.aspx)

Information subject to change without notice.

Revised June, 2018